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APPLICANT

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GROUP

2858

**INFORMATION DISCLOSURE  
STATEMENT BY APPLICANT**

(Use several sheets if necessary)



**U.S. PATENT DOCUMENTS**

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>gpa</i>	4,503,537	03/1985	McAnney	371	25	
<i>gpa</i>	6,327,687	12/2001	Rajski	714	738	

**FOREIGN PATENT DOCUMENTS**

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

**OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)**

*gpa* B. Koenemann, "LFSR-Coded Test Patterns for Scan Designs", Proc.,  
European Test Conf., pp. 237-242, 1991.

/COPY UNAVAILABLE/

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation is considered, draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.